



PATENT
Attorney Docket No. 2043/US
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Kenneth R. Wilsher et al.

Application No. 09/746,618

Filed: December 21, 2000

For: OPTICAL COUPLING FOR TESTING
INTEGRATED CIRCUITS

Confirmation No.: 2164

Art Unit: 2877

Examiner: Richard A. Rosenberger

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
Under 37 C.F.R. §§ 1.97(c)(1), 1.97(e)(1), and § 1.98

Sir:

The Examiner is requested to consider the references noted on the enclosed Form PTO-1449 during examination of the above-identified patent application. These references are submitted for the Examiner's consideration and are submitted pursuant to the duty of disclosure under 37 C.F.R. § 1.56. In submitting these references, no representation is made or implied that the references are or are not material to the examination of the application. The Examiner is encouraged to make his or her own determination of materiality. Copies of the cited documents are enclosed.

The references cited on the attached PTO-1449 were cited in a French Search Report dated January 23, 2004, of corresponding French patent application No. 0116591. A copy of the French Search Report is enclosed herewith. Further, the enclosed references include U.S. Patent No. 6,160,407, to Nikawa, as the French Search Report apparently misidentifies that reference as U.S. Patent No. 160,407, to Eubank.

Statement Under 37 C.F.R. § 1.97(e)(1)

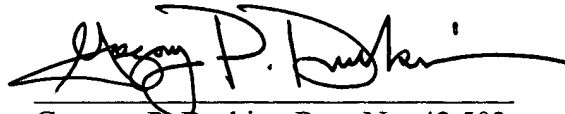
The undersigned hereby certifies that the references cited on the attached PTO-1449 were cited in a communication from a foreign patent office in a corresponding foreign application not more than three months prior to the filing of this information disclosure statement.

Pursuant to 37 C.F.R. § 1.97(c)(1) and § 1.97(e)(1), no fees are due with respect to this filing. However, should any fees be deemed necessary, such fees may be charged to Deposit Account No. 04-1415.

If the Examiner has any questions, please contact the undersigned attorney.

Dated: April 20, 2004

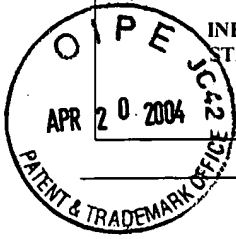
Respectfully submitted,



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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 2043/US	APPLN. NO. 09/746,618
	APPLICANT: Kenneth R. Wilsher et al.	
	FILING DATE December 21, 2000	GROUP 2877



U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		160,407	03/1875	Eubank			
		5,631,571	05/1997	Spaziani et al.	324	752	
		5,751,159	05/1998	Holm et al.	324	767	
		6,160,407	12/2000	Nikawa	324	750	

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NUMBER	PUBLISHED DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		Valdmanis, J., "Advanced Electro-Optic Sampling Permits Non-Invasive Testing of IC Performance, Electronic Engineering, Morgan-Grampian Ltd., London, GB, Vol. 61, No. 756, pp. 35, 36, 40, 42 (February 1, 1989).

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.